

Notice of References Cited	Application/Control No. 10/522,468	Applicant(s)/Patent Under Reexamination CHANG, WEI-BIN	
	Examiner Leonard Saint-Cyr	Art Unit 2626	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0152246	10-2002	Critchlow, Richard Lee	707/535
*	B	US-2003/0152261	08-2003	Hiroe et al.	382/153
	C	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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